

Supporting Information for

Monolithic in-plane integration of gate-modulated switchable supercapacitors (*ipG-Cap*)

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Methods

Calculation and normalization of capacitances

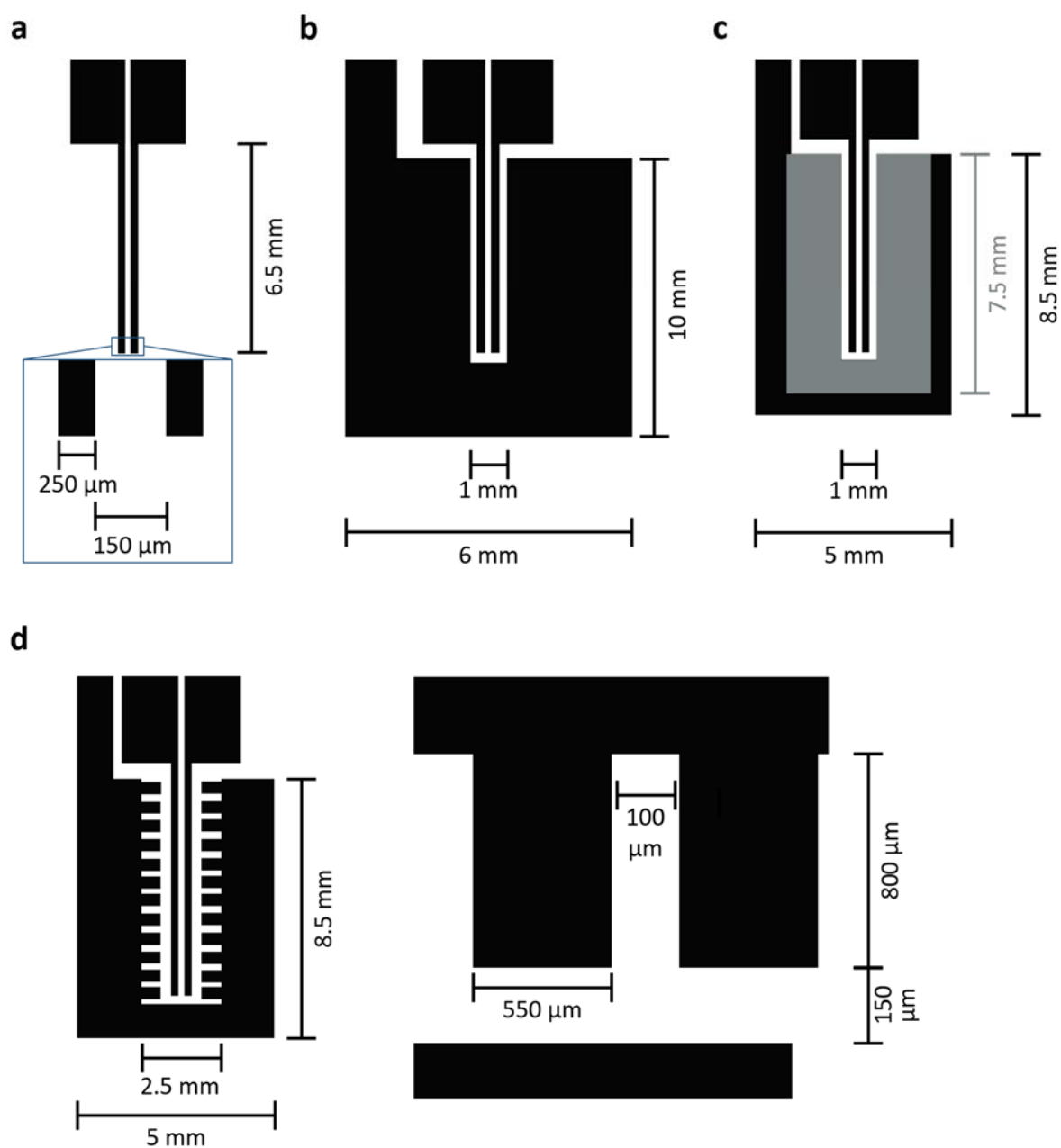
The capacitance of interdigital SCs was determined by cyclic voltammetry. The integrated area A_{CV} is divided by the potential range ΔU and the scan rate ν (1). The following equation for capacitance calculation is used:

$$C = \frac{\int_0^1 I \, dU}{\Delta U \, \nu} \quad (1)$$

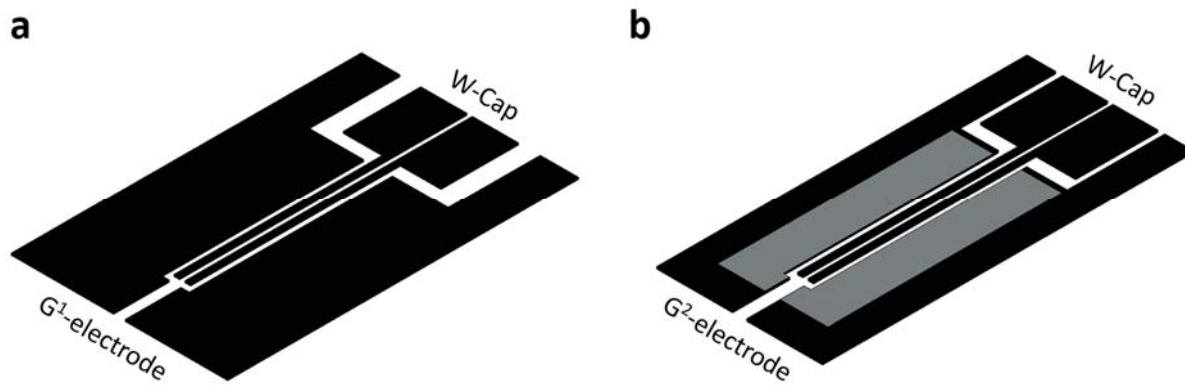
For comparison to other energy storage systems, the capacitances were normalized to the device area A_D including the total electrode and electrolyte area in the following equation (2):

$$C_{\text{Device}} = \frac{C}{A_D} \quad (2)$$

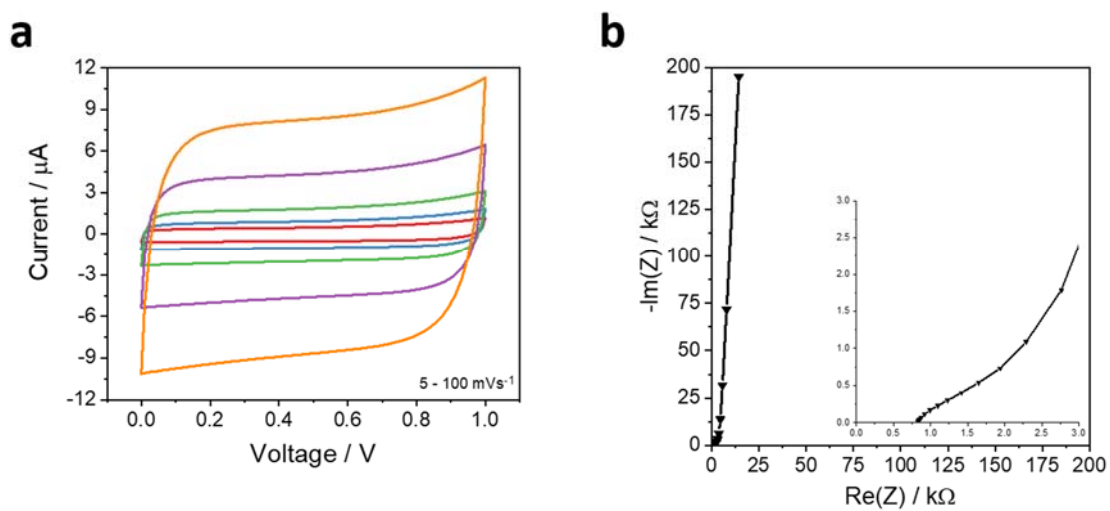
Supplementary figures



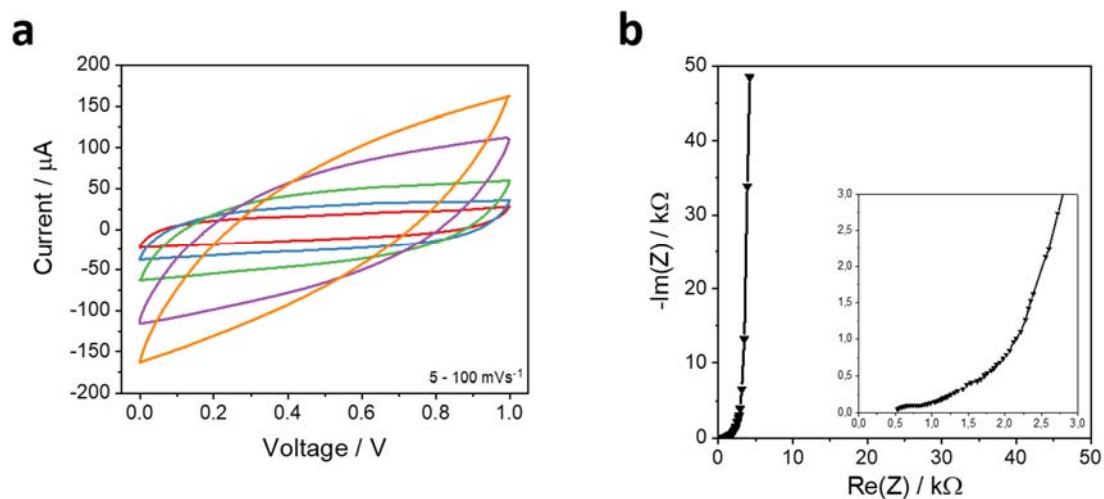
Supplementary Figure 1. Dimensions of the simplified interdigitated W-Cap (a) and of G-electrode architectures for in-plane G-Cap devices in 1st generation (b), 2nd generation (c), 3rd generation (d).



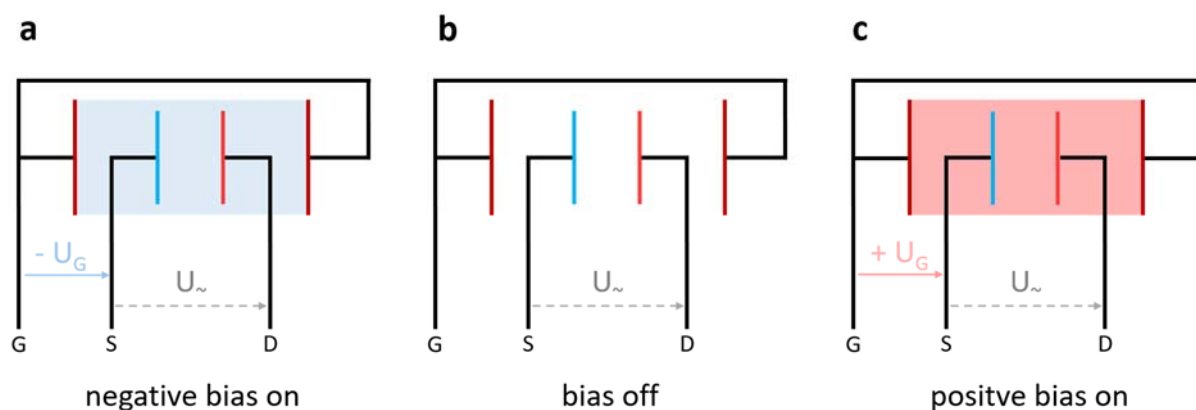
Supplementary Figure 2. Schematic illustration of devices with divided gate electrodes. 1st generation (a), 2nd generation (b).



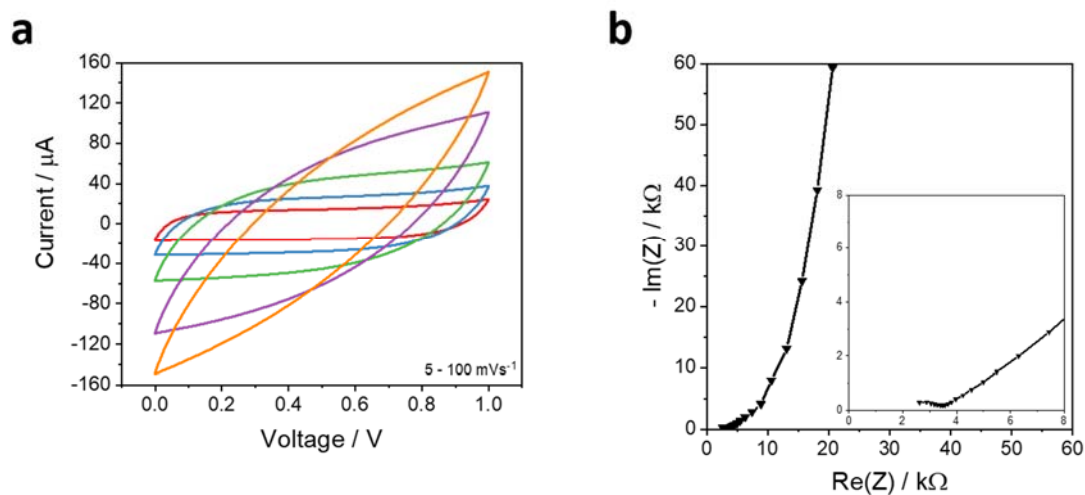
Supplementary Figure 3. Cyclic voltammograms of the simplified interdigitated W-Cap at varying scan rates (a) and the Nyquist plot (b).



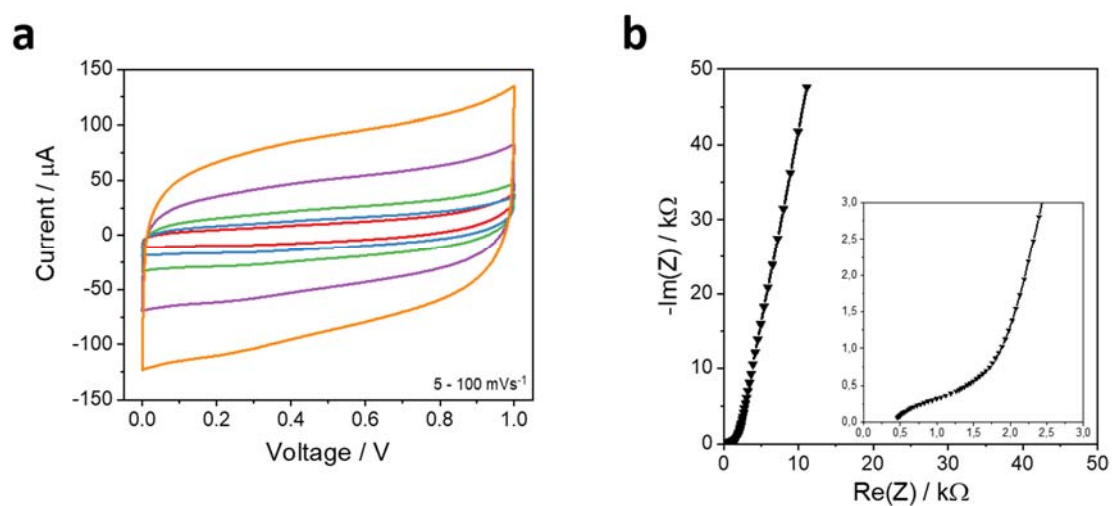
Supplementary Figure 4. Cyclic voltammograms of sucrose-derived carbon G-electrode ($ip\text{-}G^1$) at varying scan rates (a) and the Nyquist plot (b).



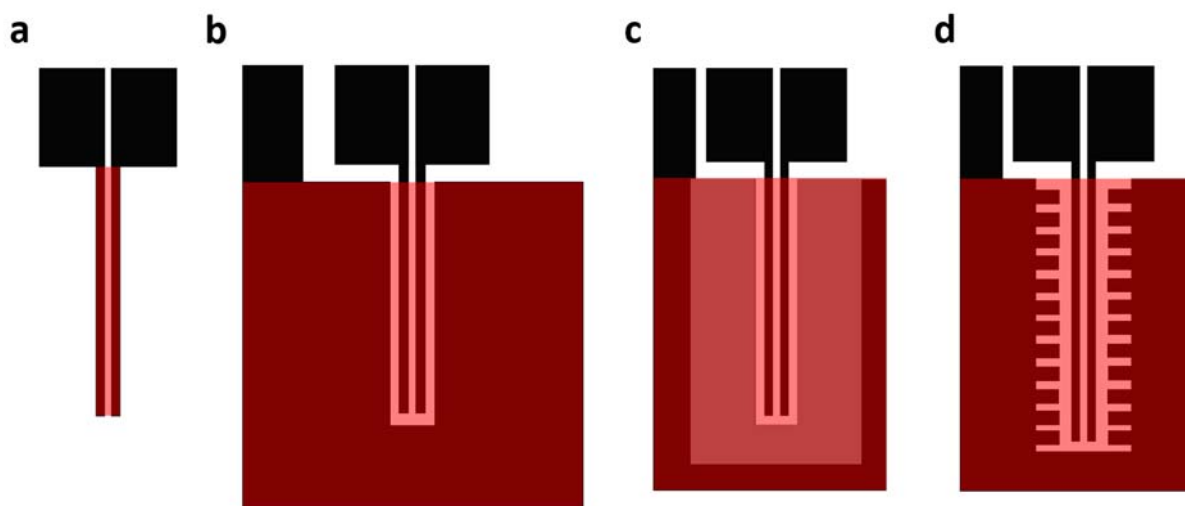
Supplementary Figure 5. Electric circuit diagrams for different sections of the measurement: blue negative bias on ($-U_G = -1.0$ V) for W-Cap switching “off” (a), bias off (b) and red positive bias ($U_G = +1.0$ V) for switching W-Cap back to “on” (c).



Supplementary Figure 6. Cyclic voltammograms of sucrose-derived carbon G-electrode ($ip-G^2$) at varying scan rates (a) and the Nyquist plot (b).



Supplementary Figure 7. Cyclic voltammograms of sucrose-derived carbon G-electrode ($ip-G^3$) at varying scan rates (a) and the Nyquist plot (b).



Supplementary Figure 8. Structures of the simplified interdigitated W-Cap (a) and of G-electrode architectures for in-plane G-Cap devices in 1st generation (b), 2nd generation (c), 3rd generation (d) with the red marked device area (A_D).

Supplementary Tables

Supplementary Table 1. Rate-dependent capacitances of the W-Cap and the ipG^1 -electrode based EDLC (ipG^1 -Cap).

Scan rates [mV s ⁻¹]	W-Cap		Gate electrode	
	Capacitance [mF]	Device capacitance	Capacitance [mF]	Device capacitance
		[mF cm ⁻²]		[mF cm ⁻²]
5	0.21	1.6	5.3	8.8
10	0.20	1.5	4.9	8.2
20	0.19	1.5	3.4	5.7
50	0.18	1.3	2.6	4.3
100	0.16	1.2	1.6	2.7

Supplementary Table 2. Rate-dependent capacitances of *ipG*²-electrode based EDLC (*ipG*²-Cap).

Scan rates [mV s ⁻¹]	G ² -electrode	
	Capacitance [mF]	Device capacitance [mF cm ⁻²]
5	5.2	12.2
10	4.6	10.9
20	3.4	8.1
50	2.2	5.2
100	1.2	2.8

Supplementary Table 3. Rate-dependent capacitances of *ipG*³-electrode based EDLC (*ipG*³-Cap).

Scan rates [mV s ⁻¹]	G ³ -electrode	
	Capacitance [mF]	Device capacitance [mF cm ⁻²]
5	3.0	7.1
10	2.4	5.7
20	2.2	5.0
50	1.9	4.5
100	1.7	3.9